

TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

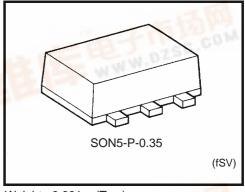
TC7SH02FS

2-INPUT NOR GATE

Features

High speed: $t_{pd}=3.6$ ns (typ.) at $V_{CC}=5$ V Low power dissipation: $I_{CC}=2$ μA (max) at $Ta=25^{\circ}C$ High noise immunity: $V_{NIH}=V_{NIL}=28\%$ V_{CC} (min) 5.5V tolerant input.

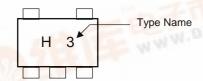
Wide operating voltage range: V_{CC} (opr) = 2~5.5 V

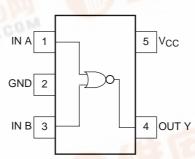


Weight: 0.001 g (Typ.)

Marking

Pin Assignment (top view)







Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V _{CC}	-0.5~7.0	V
DC input voltage	V _{IN}	-0.5~7.0	V
DC output voltage	V _{OUT}	−0.5~V _{CC} + 0.5	٧
Input diode current	I _{IK}	-20	mA
Output diode current	lok	±20	mA
DC output current	lout	±25	mA
DC V _{CC} /ground current	Icc	±50	mA
Power dissipation	PD	50	mW
Storage temperature	T _{stg}	-65~150	°C

Logic Diagram



Truth Table

Α	В	Υ
L	L	Н
L	Н	L
Н	L	L
Н	Н	L

Recommended Operating Conditions

Characteristics	Symbol	Rating	Unit	
Supply voltage	V _{CC}	2.0~5.5	V	
Input voltage	V _{IN}	0~5.5	V	
Output voltage	V _{OUT}	0~Vcc	V	
Operating temperature	T _{opr}	-40~85	°C	
Input rise and fall time	dt/dv	0~100 (V _{CC} = 3.3 ± 0.3 V)	ns/V	
input rise and rail time	αί/αν	$0 \sim 20 \; (V_{CC} = 5 \pm 0.5 \; V)$	115/ V	

Electrical Characteristics

DC Characteristics

Characteristics Symbol		Test			Ta = 25°C			Ta = -40~85°C			
		Circuit	Test Condition			Min	Тур.	Max	Min	Max	Unit
High-level input						1.50	_	_	1.50	_	
voltage	V _{IH}			_	3.0~ 5.5	V _{CC} × 0.7		_	V _{CC} × 0.7	_	V
Low lovel input	Landan Canad				2.0	_		0.50	_	0.50	
voltage	Low-level input voltage		_		3.0~ 5.5	_	_	V _{CC} × 0.3	_	V _{CC} × 0.3	V
			$V_{IN} = V_{IL}$	Ι _{ΟΗ} = -50 μΑ	2.0	1.9	2.0	_	1.9	_	V
					3.0	2.9	3.0	_	2.9	_	
High-level output voltage VOH	VoH	_			4.5	4.4	4.5	_	4.4	_	
				$I_{OH} = -4 \text{ mA}$	3.0	2.58		_	2.48	_	
				$I_{OH} = -8 \text{ mA}$	4.5	3.94		_	3.80	_	
Low-level output voltage					2.0	_	0.0	0.1	_	0.1	
	_	V _{IN} = V _{IH}	I _{OL} = 50 μA	3.0	_	0.0	0.1	_	0.1	V	
				4.5	_	0.0	0.1	_	0.1		
			0. 12	I _{OL} = 4 mA	3.0	_	_	0.36	_	0.44	
				I _{OL} = 8 mA	4.5	_	_	0.36	_	0.44	
Input leakage current	I _{IN}	_	V _{IN} = 5.5 V or GND		0~ 5.5	_		±0.1		±1.0	μА
Quiescent supply current	Icc	_	V _{IN} = V _{CC} or GND			_	_	2.0	_	20.0	μА

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AC Characteristics (Input: $t_r = t_f = 3 \text{ ns}$)

Characteristics Sym	Cumbal	Test Circuit	Т	est Conditio	est Condition		Ta = 25°C			Ta = -40~85°C	
	Symbol			V _{CC} (V)	C _L (pF)	Min	Тур.	Max	Min	Max	Unit
Propagation delay time	^t pLH t _{pHL}	_	_	3.3 ± 0.3	15	_	5.6	7.9	1.0	9.5	- ns
					50		8.1	11.4	1.0	13.0	
				5.0 ± 0.5	15	_	3.6	5.5	1.0	6.5	
					50	_	5.1	7.5	1.0	8.5	
Input capacitance	C _{IN}	_		_		_	4	10	_	10	pF
Power dissipation capacitance	C _{PD}	_			(Note)	_	15	_	_	_	pF

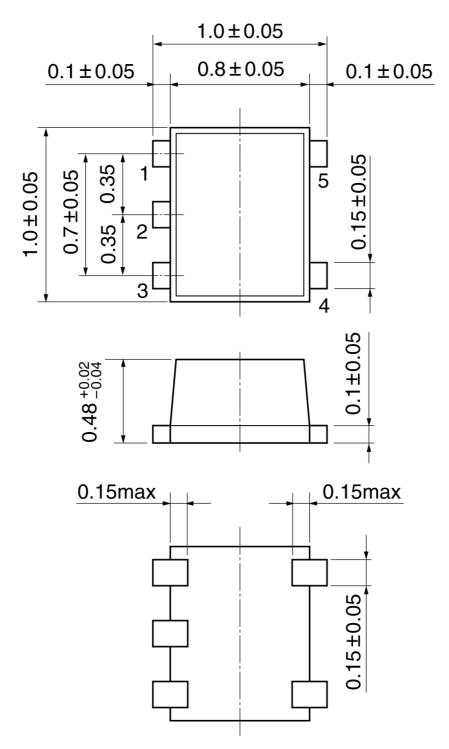
Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

$$I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

Package Dimensions

SON5-P-0.35 Unit:mm



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Weight: 0.001 g (typ.)

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